


<b>Search Notes</b>  	<b>Application/Control No.</b>  110784446	<b>Applicant(s)/Patent Under Reexamination</b>  EYAL, AVIV
	<b>Examiner</b>  Krisna Lim	<b>Art Unit</b>  2453

SEARCHED			
Class	Subclass	Date	Examiner
709	231, 245, 223	2/4/09	kl
707	10, 223	2/4/09	kl
345	327	2/4/09	kl

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor	2/4/09	kl

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--